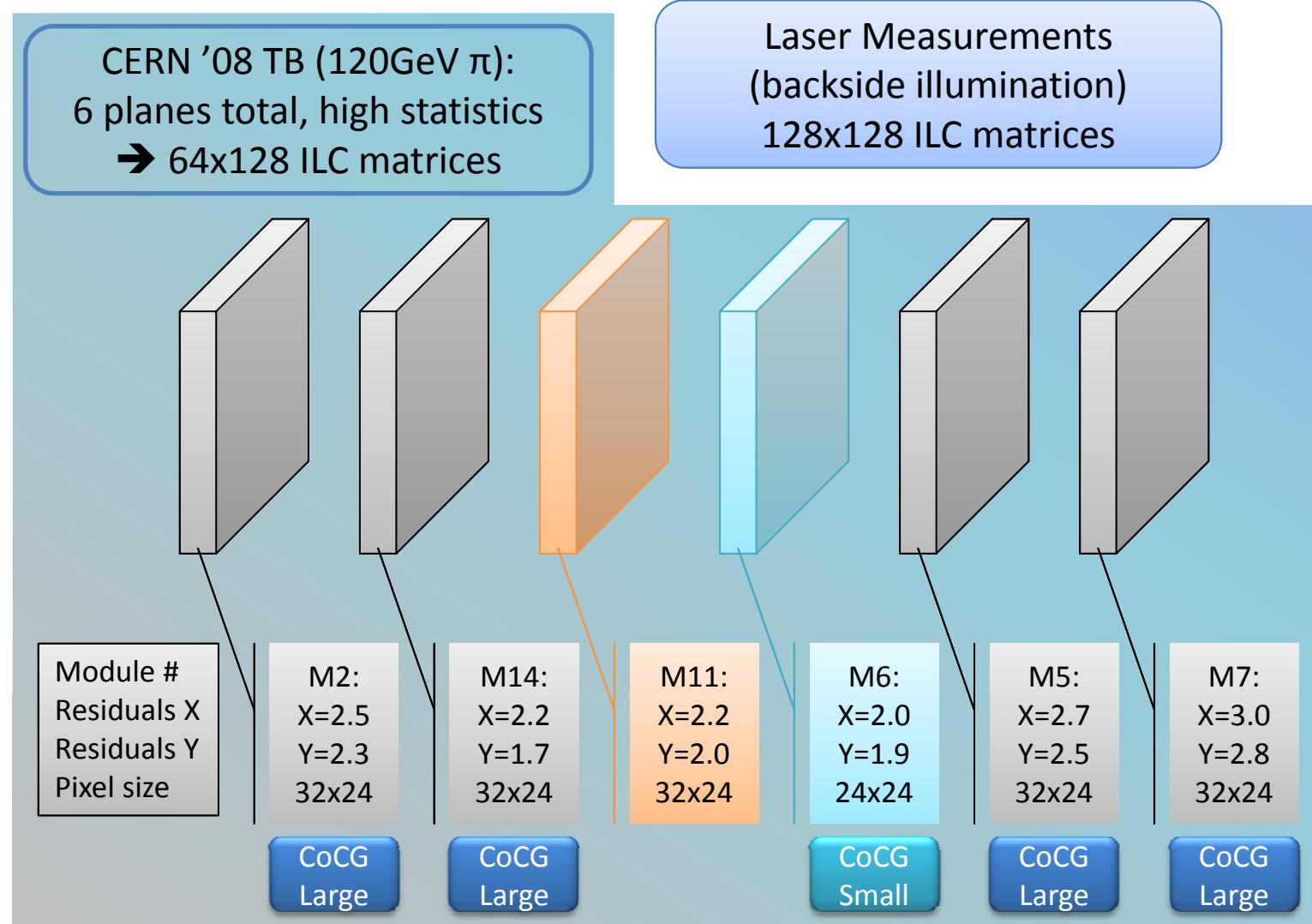


In pixel test beam studies

Lars Reuen, Bonn

What data are we looking at?

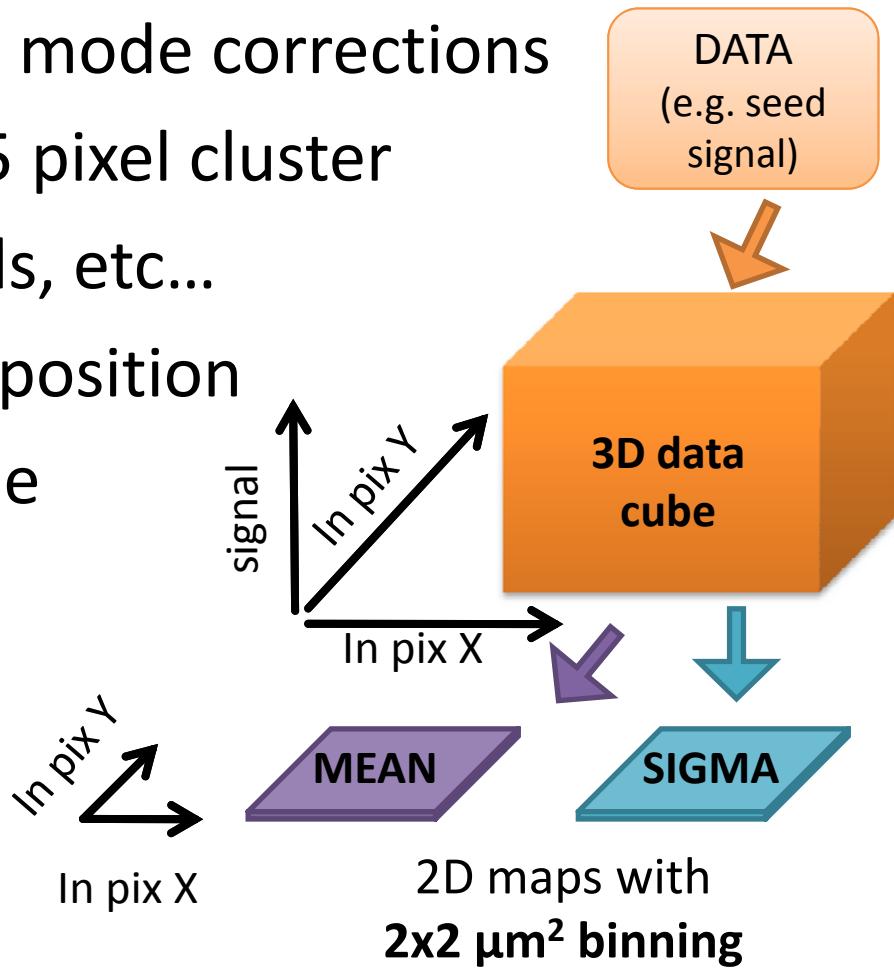
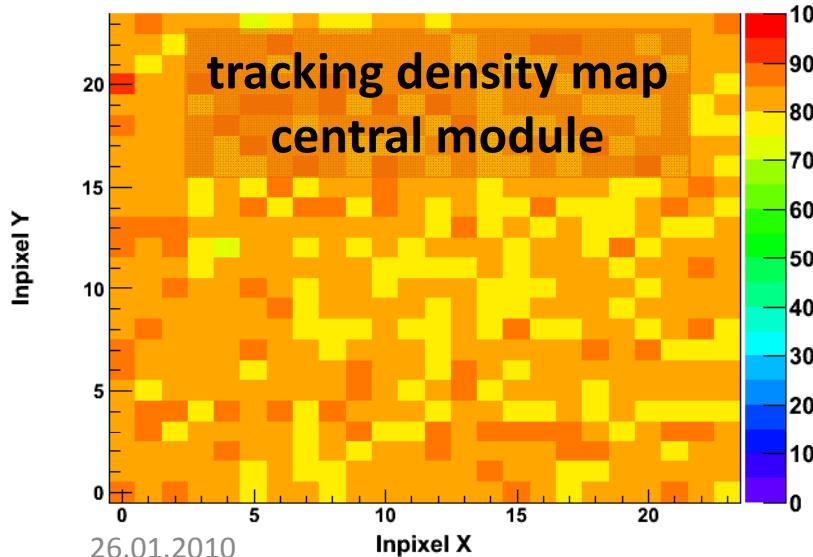


What was studied...

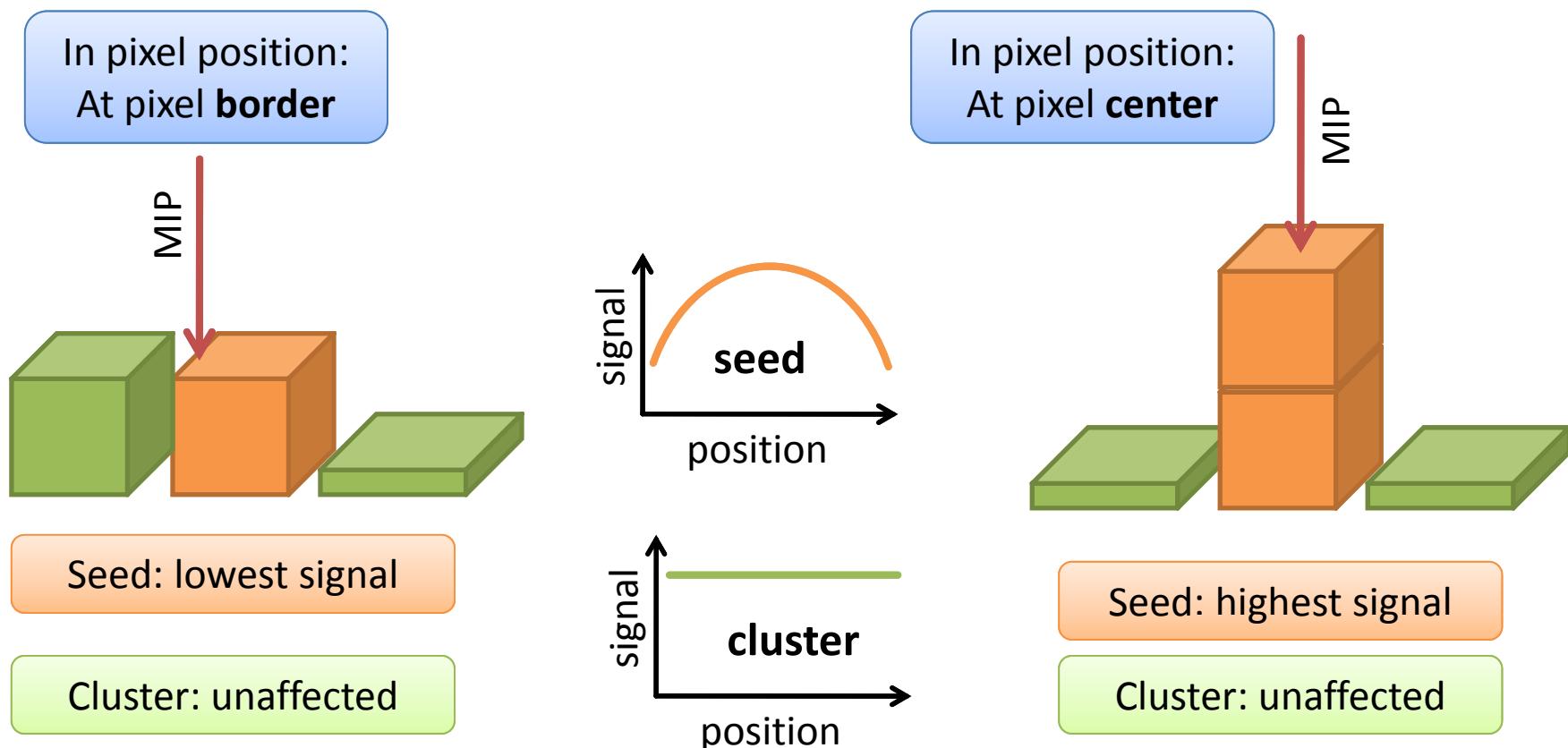
- In pixel studies
 - ➔ high resolution (1-2 μm)
 - ➔ high statistics (first time, total 4 TB data)
- Various properties:
 - ➔ Seed Signal
 - ➔ Cluster Signal
- Two layout type: Common Clear Gate (CoCG)
 - ➔ CoCG Large $32 \times 24 \mu\text{m}^2$
 - ➔ CoCG Small $24 \times 24 \mu\text{m}^2$

How was the data analyzed

- Pedestal, noise, common mode corrections
- Iterative seed search, 5x5 pixel cluster
- Cuts on hot or noisy pixels, etc...
- Alignment & tracking → position
- All pixels combined to one



seed & cluster signals: what to expect



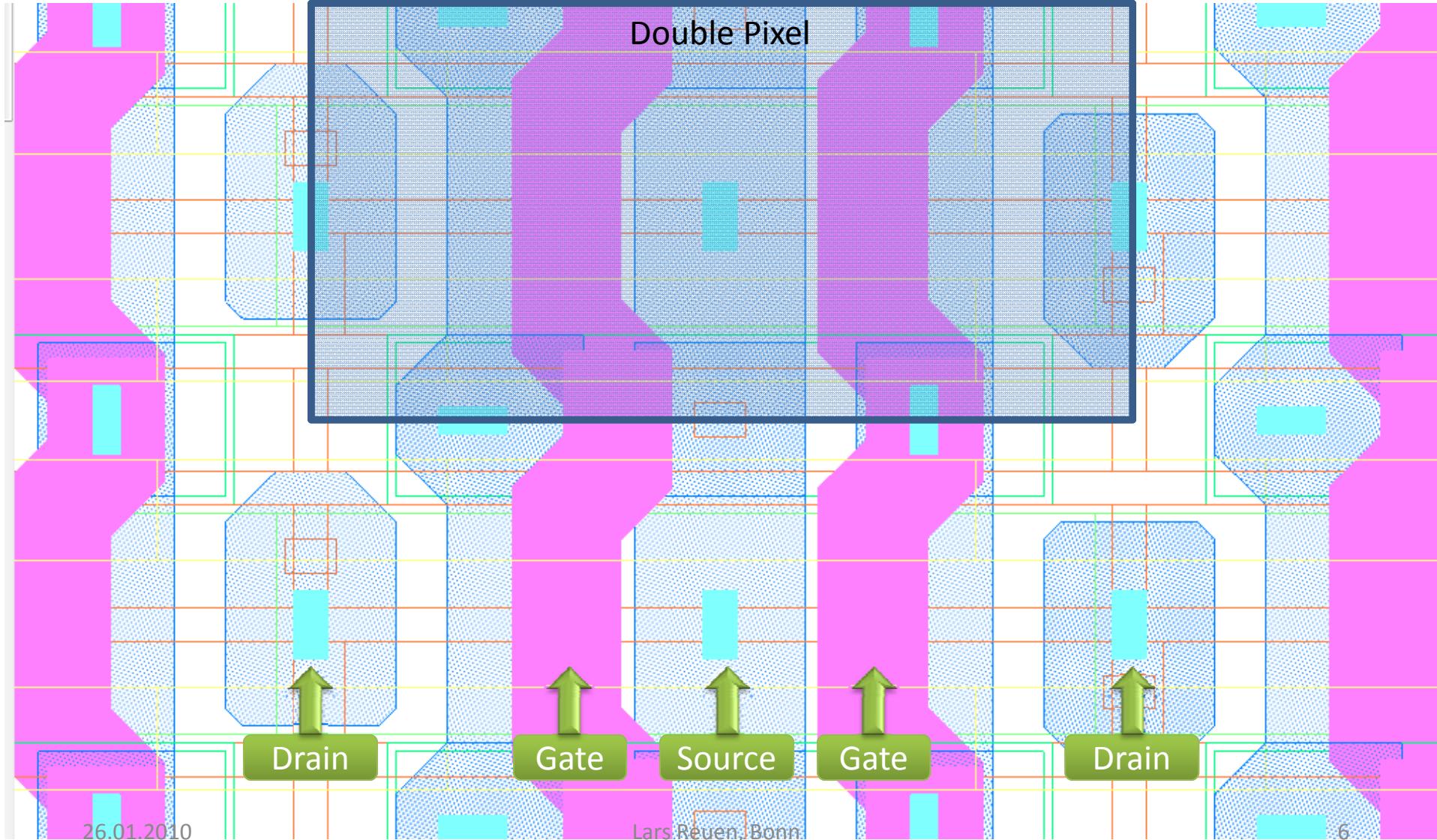
COCG Small Pixel Layout

Switcher

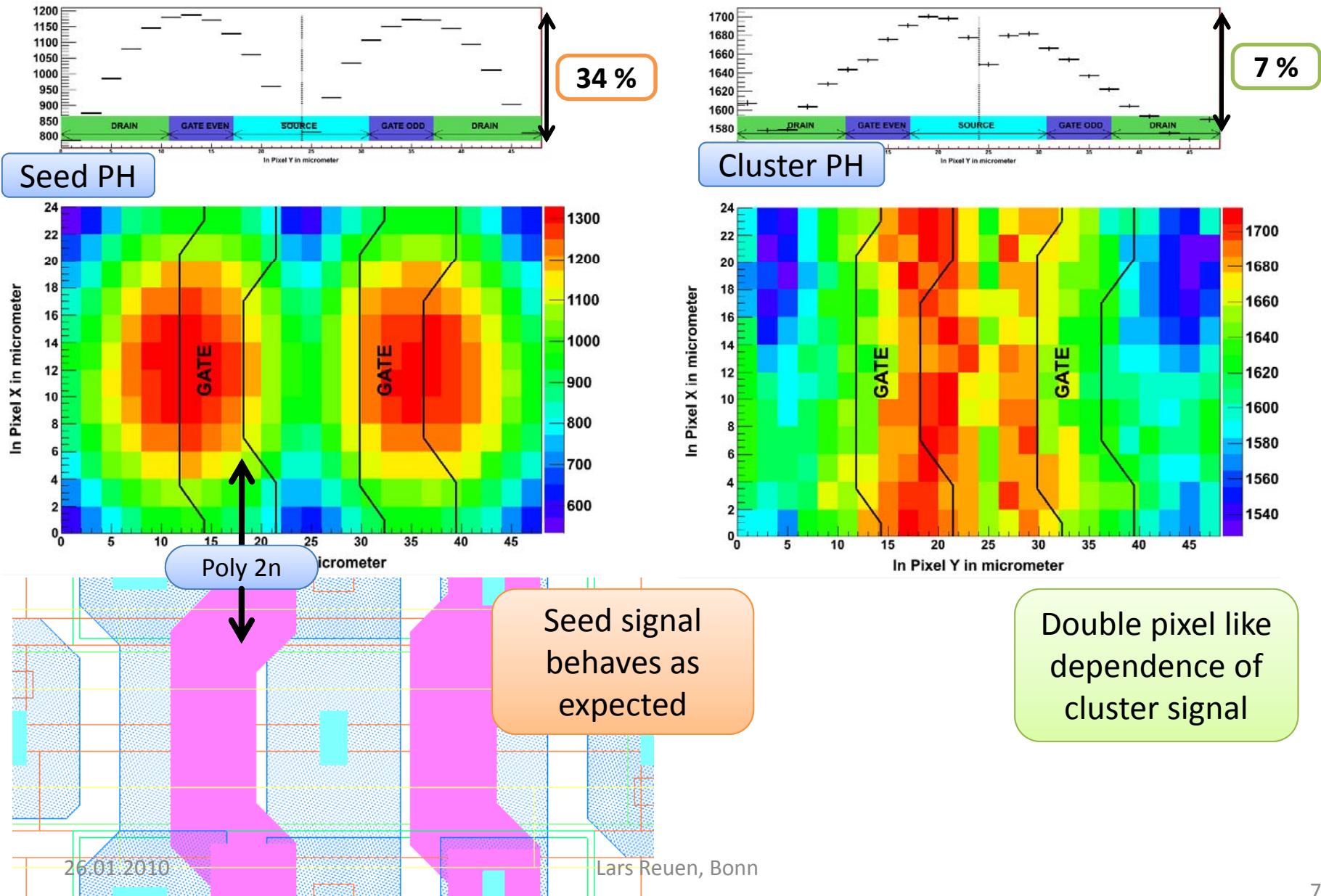
RO

CUR0

Switcher



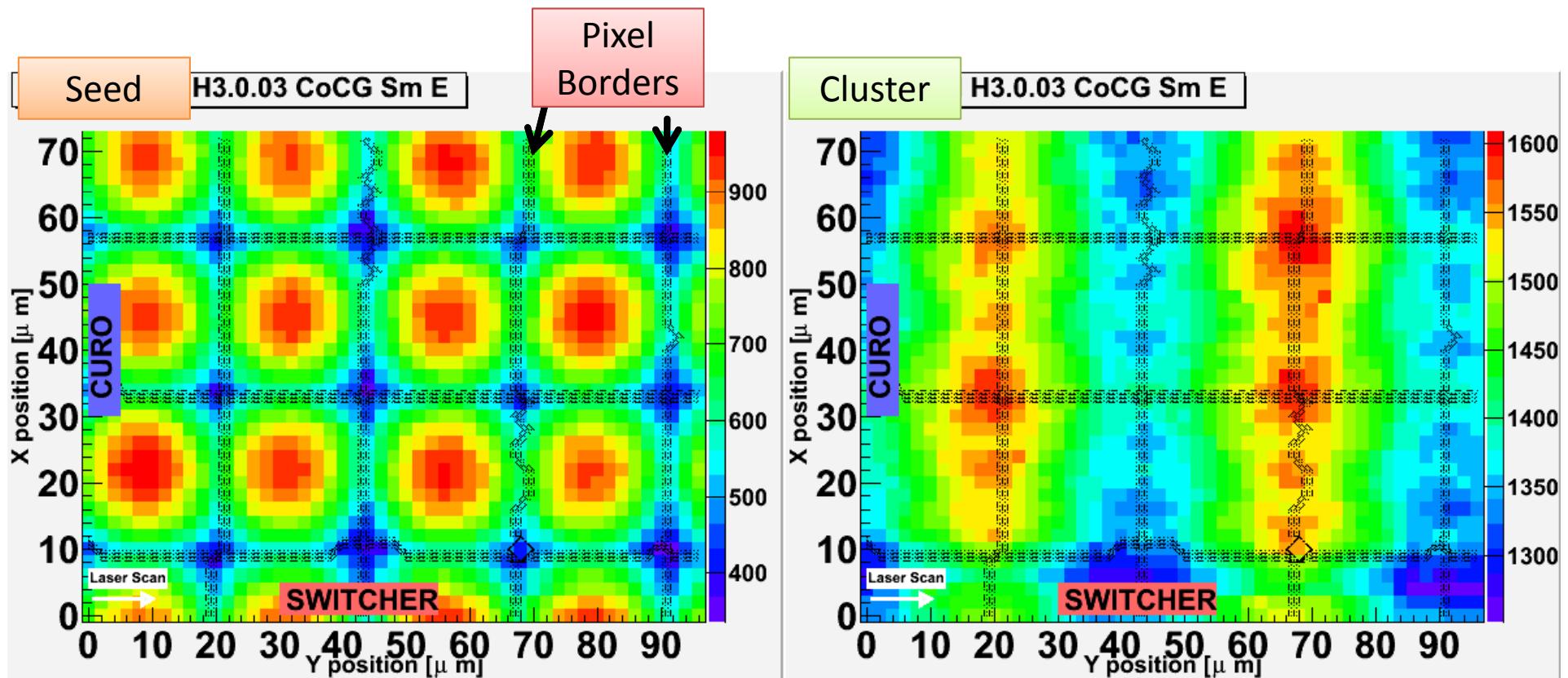
Module 6 (CoCG SMALL): Test Beam Data



Laser measurement COCG Small

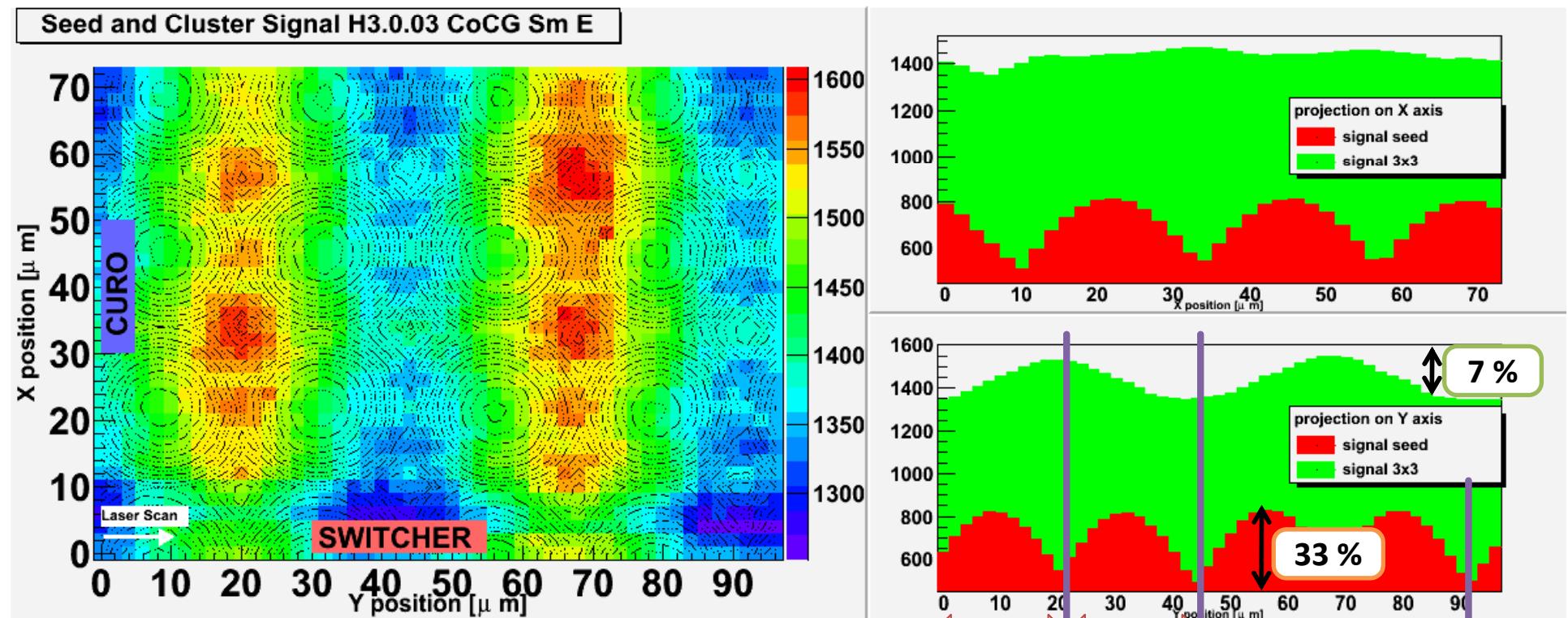
Can we confirm the effect
with an independent
measurement?

→ Laser instead of MIP,
→ 128x128 pixel matrix
(same layout: COCG small)



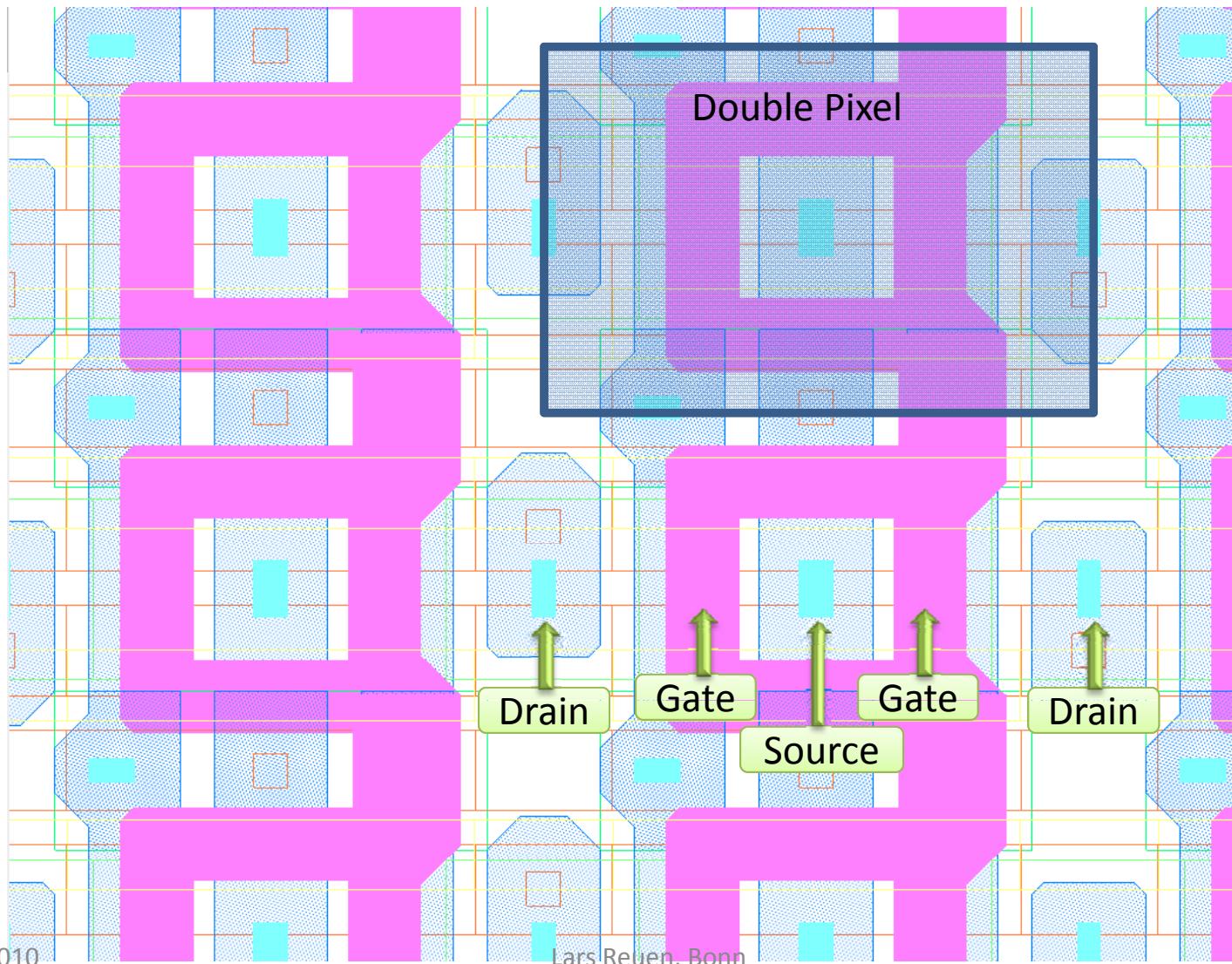
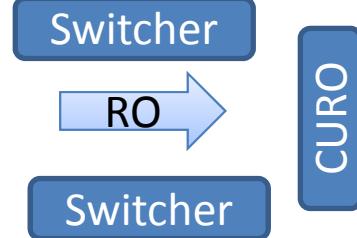
Laser measurement COCG Small

Contour = Seed, Color = Cluster

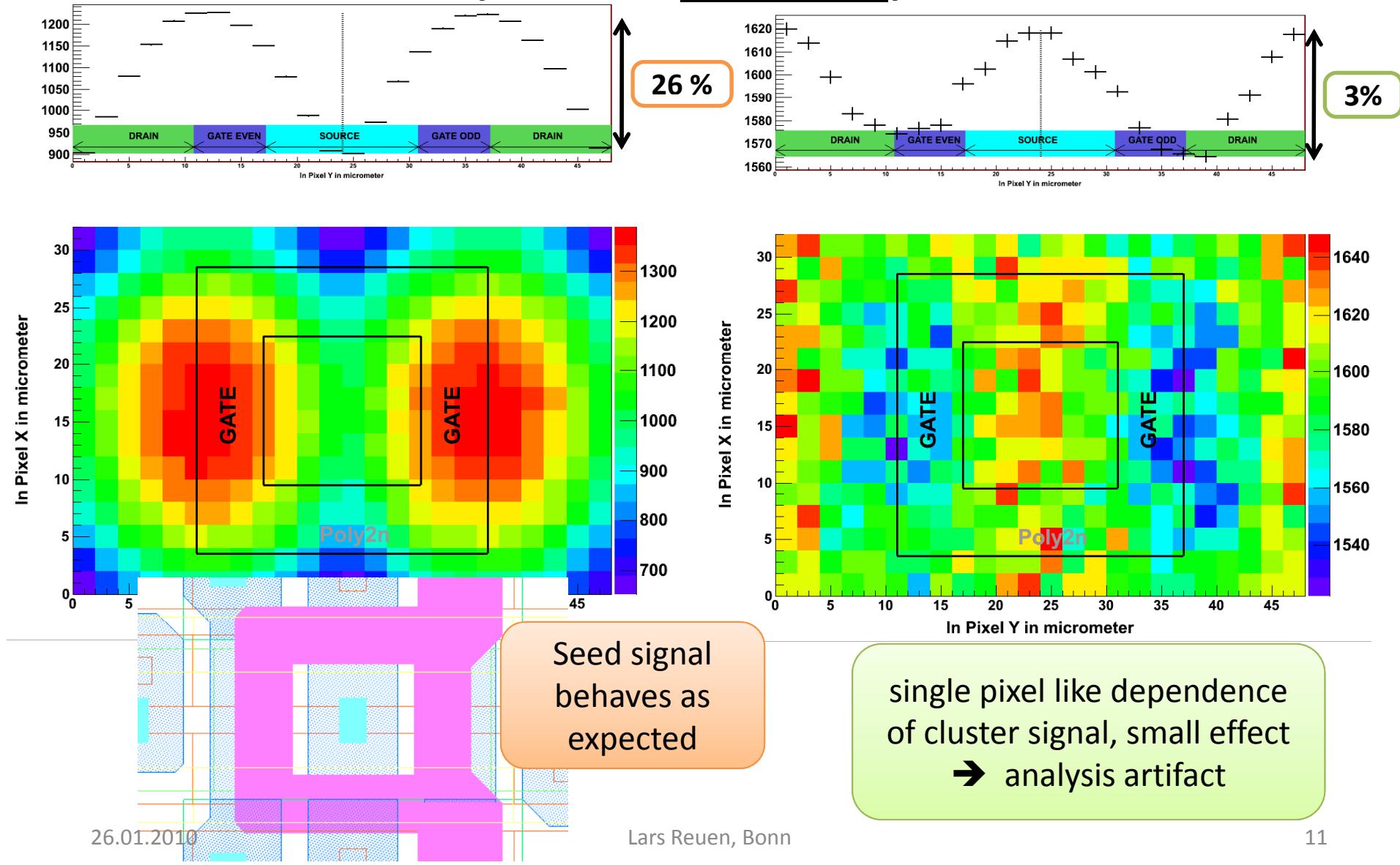


Laser measurement confirms:
In-pixel cluster signal dependence
correlated to double pixel structure

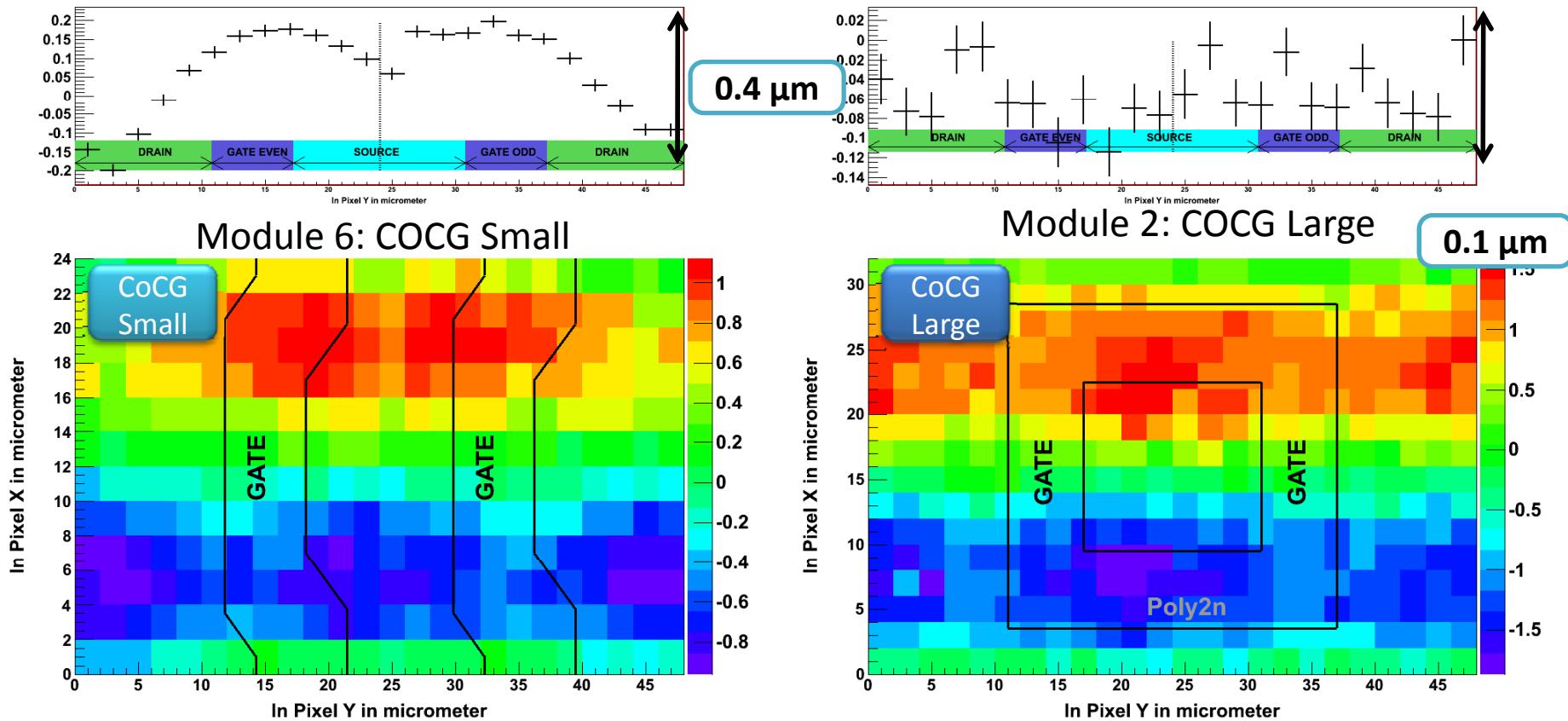
COCG Large Pixel Layout



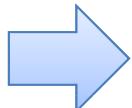
Module 2 (CoCG LARGE): Test Beam



Do we have to worry? No!



Check effect
on residuals:
plot X vs. Y



no effects
from position
reconstruction

Minimal effect
on X residuals
→ negligible

Possible explanation

- Ballistic deficit under source
- Potential difference between gate & source less than between gate & drain
- Possible test:
 - Laser scan with slower/faster read out
 - effect should become more/less prominent

Summary

- In pixel studies with TB “08 basically finished
- Most properties vs. in pixel position as expected
- Interesting but very small effect of cluster signal dependence on in pixel (Y) position with one layout type
 - ➔ effect on position reconstruction is insignificant
 - ➔ more of academic than practical concern